Test probe, INGUN S-Line

S-075 214 050 A 2200 ES

Item S-075-0038

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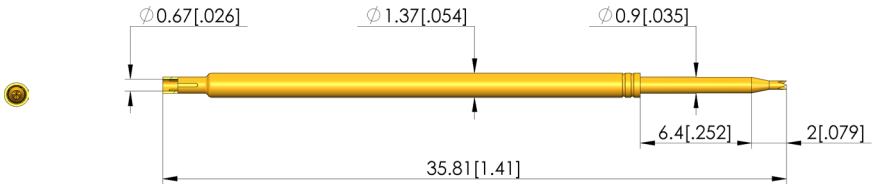
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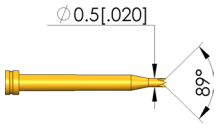
- Use of larger test probes for increased contacting accuracy and longer service life
- Minimal grid dimensions due to omission of receptacles (socketless)
- Large selection of tip styles and spring forces for optimal contact with the test point
- Compatible with existing socketless systems

NEW



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General data

Product group:	ICT / FCT (in-circuit test and function test
Sub-product group:	INGUN S-Line
Series:	S-075 ES standard with increased spring pre-load
Grid:	1.91 mm [75 mil]
Contacting from:	Pad, pin, posts
Magnetic:	Yes
Installation type:	Plug-in
Quick-exchange system:	Yes
Type of test probe connection:	Contact terminal
Adjustable installation height:	No
Non-rotating:	No
Min. temperature:	- 40 °C [- 104 °F]
Max. temperature:	+ 80 °C [+ 176 °F]
RoHS-compliant:	RoHS-3;6a

Electrical data

Current load capacity / rated current:	5 A
Typical resistance (Ri):	<20 mOhm

Mechanical data

Total length:	35.81 mm [1.40 in]
Barrel diameter:	1.37 mm [.053 in]
Maximum stroke:	6.35 mm [.25 in]
Spring pre-load:	1.44 N [5.17 ozf]
Collar height:	00
Spring force at working stroke:	2.25 N [8.09 ozf]
Recommended working stroke:	4.3 mm [.169 in]
Mounting hole in probe plate (KTP):	1.39 - 1.41 mm [.054 - .055 in]
Mounting hole in S-Line spacer plate (SDP):	min. 1.58 mm [.062 in]
KT designation:	KT-S050#KT-S075

Tip style data

Tip style:	14 4-point crown, self-cleaning
Tip diameter:	0.5 mm [.019 in]
Tip style surface:	A gold
Tip style material:	2 steel

ICT/FCT TEST PROBES

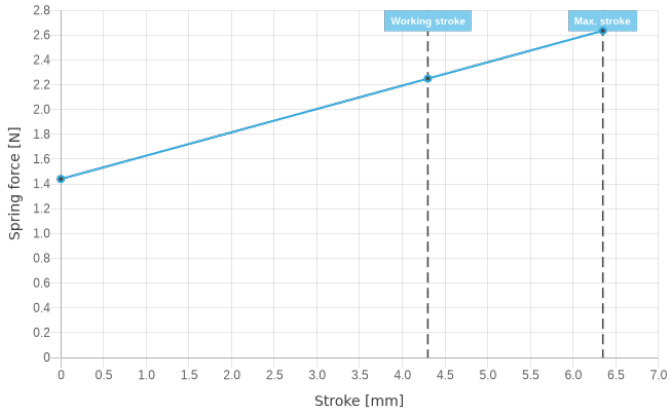
Test probe, INGUN S-Line

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